Search Notes					

Application/Control No.	Applicant(s)/Patent under Reexamination
10/711,534	YEH, JIH-CHEN
Examiner	Art Unit
Stephen J. Kalafut	1745

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SEARCHED				
Class	Subclass	Date	Examiner	
429	96, 97, 99, 100, 174	7/16/2007	SJK	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
SNUS	Afor	1/28/08	SK	
		16		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
eDAN Inventor Name Search	7/16/2007	SJK
EAST: USPAT, USPGPUB, USOCR, DERWENT, JPAB, EPAB	· 7/16/2007	SJK
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